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Substitute Form PTO-1449 (Modified)		U.S. Department of Commerce Patent and Trademark Office	Attorney's Docket No. 09712-213002	Application No.
Information Disclosure Statement by Applicant (Use several sheets if necessary) (37 CFR §1.98(b))		Applicant Peter J. de Groot et al.		
		Filing Date March 22, 2004	Group Art Unit	

U.S. Patent Documents							
Examiner Initial	Desig. ID	Document Number	Publication Date	Patentee	Class	Subclass	Filing Date If Appropriate
	AA	4,743,117	05/1988	Kitabayashi et al.	356	520	
	AB	2003/0043385	03/2003	Kuchel, Michael	356	513	
	AC	2003/0011783	01/2003	Suzuki et al.	356	512	
	AD	5,485,275	01/1996	Ohtsuka, Masaru	356	513	
	AE	4,898,470	02/1990	Cleaveland, Edwin E.	356	513	
	AF	4,387,994	06/1983	Balasubramanian, N.	356	513	
	AG	2001/0028462	10/2001	Ichihara et al.	356	512	
	AH						
	AI						
	AJ						
	AK						

Foreign Patent Documents or Published Foreign Patent Applications							
Examiner Initial	Desig. ID	Document Number	Publication Date	Country or Patent Office	Class	Subclass	Translation
							Yes No
	AL						
	AM						
	AN						
	AO						
	AP						

Other Documents (include Author, Title, Date, and Place of Publication)		
Examiner Initial	Desig. ID	Document
	AQ	
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	AS	
	AT	

Examiner Signature	Date Considered
EXAMINER: Initials citation considered. Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.	

Substitute Form PTO-1449 (If Modified)	U.S. Department of Commerce Patent and Trademark Office	Attorney's Docket No. 09712-213001	Application No. 10/190,353
Information Disclosure Statement by Applicant (Use several sheets if necessary)		Applicant Peter de Groot et al.	
		Filing Date July 3, 2002	Group Art Unit 2877
(37 CFR §1.98(b))			

U.S. Patent Documents							
Examiner Initial	Desig. ID	Document Number	Publication Date	Patentee	Class	Subclass	Filing Date If Appropriate
	AA	6,195,168	2/27/2001	De Lega et al.	356	497	
	AB	6,154,279	11/28/2000	Thayer	356	376	
	AC	5,991,035	11/23/1999	Bruning	356	359	
	AD	5,784,164	7/21/1998	Deck et al.	356	359	
	AE	5,398,113	3/14/1995	de Groot	356	360	
	AF	4,872,755	10/10/1989	Küchel	356	360	
	AG	4,340,306	7/20/1982	Balasubramanian	356	360	
	AH						
	AI						

Foreign Patent Documents or Published Foreign Patent Applications							
Examiner Initial	Desig. ID	Document Number	Publication Date	Country or Patent Office	Class	Subclass	Translation
							Yes No
	AJ	WO 02/14845	2/21/2002	WIPO	G01N	21/954	
	AK	WO 01/75395	10/11/2001	WIPO	G01B	11/30	
	AL	WO 01/27558	4/19/2001	WIPO	G01B	11/30	
	AM						
	AN						

Other Documents (include Author, Title, Date, and Place of Publication)		
Examiner Initial	Desig. ID	Document
	AO	Boppert et al., "Forward-imaging instruments for optical coherence tomography", <u>Optics Letters</u> , Vol. 22, No. 21, pp. 1618-1620 (November 1, 1997)
	AP	Blümel et al., "Absolute interferometric calibration of toric and conical surfaces", <u>SPIE</u> , Vol. 3134, pp. 370-378 (July 1997)
	AQ	Brinkman et al., "Testing of rod objects by grazing-incidence interferometry: experiment", <u>Applied Optics</u> , Vol. 38, No. 1, pp. 121-125 (January 1, 1999)
	AR	Chakmakjian et al., "Simultaneous focus and coherence scanning in interference microscopy", <u>Technical Digest, International Workshop on Interferometry</u> , 171 (Riken, Japan, 1996)
	AS	Dresel et al., "Three-dimensional sensing of rough surfaces by coherence radar", <u>Applied Optics</u> , Vol. 31, No. 7, pp. 919-925 (March 1, 1992)
	AT	Li et al., "Imaging needle for optical coherence tomography", <u>Optics Letters</u> , Vol. 25, No. 20, pp. 1520-1522 (October 15, 2000)

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		Filing Date July 3, 2002	Group Art Unit 2877	
(37 CFR §1.98(b))				

Other Documents (include Author, Title, Date, and Place of Publication)		
Examiner Initial	Desig. ID	Document
	BA	Lindner et al., "White-light interferometry via an endoscope", <u>SPIE</u> , Vol. 4777, pp. 90-101 (July 2002)
	BB	Matthys et al., "Panoramic Holointerferometry", <u>Experimental Mechanics</u> , Vol. 35, No. 1, pp. 83-88 (March 1995)
	BC	Schwider, "White-light Fizeau interferometer", <u>Applied Optics</u> , Vol. 36, No. 7, pp. 1433-1437 (March 1, 1997)
	BD	Zhou et al., "Surface profile measurements using a white light Linnik interferometer", <u>Annual Report Lehrstuhl für Optik, Univ. Erlangen-Nürnberg</u> pp. 69 (1996)
	BE	
	BF	

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				Filing Date July 3, 2002	Group Art Unit 2877

U.S. Patent Documents							
Examiner Initial	Desig. ID	Document Number	Publication Date	Patentee	Class	Subclass	Filing Date If Appropriate
	AA	5,293,214	3/8/1994	Ledger	356	355	
	AB	4,725,144	2/16/1988	Nelson et al.	356	360	
	AC						
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